# **UNRF1AM**

### Silicon PNP epitaxial planar type

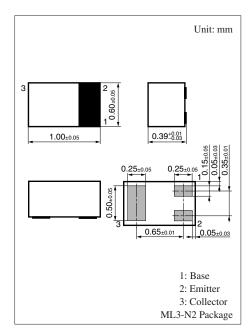
#### For digital circuits

#### ■ Features

Suitable for high-density mounting and downsizing of the equipment for Ultraminiature leadless package
 0.6 mm × 1.0 mm (height 0.39 mm)

### ■ Absolute Maximum Ratings $T_a = 25$ °C

| Parameter                             | Symbol           | Rating      | Unit |  |
|---------------------------------------|------------------|-------------|------|--|
| Collector-base voltage (Emitter open) | V <sub>CBO</sub> | -50         | V    |  |
| Collector-emitter voltage (Base open) | V <sub>CEO</sub> | -50         | V    |  |
| Collector current                     | $I_C$            | -80         | mA   |  |
| Total power dissipation               | $P_{T}$          | 100         | mW   |  |
| Junction temperature                  | $T_{j}$          | 125         | °C   |  |
| Storage temperature                   | T <sub>stg</sub> | -55 to +125 | °C   |  |



Marking Symbol: 1S

#### Internal Connection

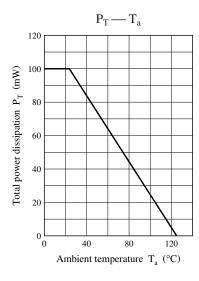
$$\begin{array}{c}
R_1 (2.2 \text{ k}\Omega) \\
\text{B} \circ - \text{W} \\
R_2 \\
(47 \text{ k}\Omega)
\end{array}$$

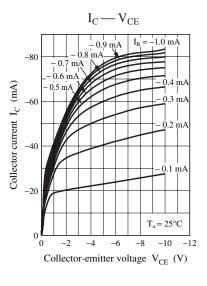
### ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

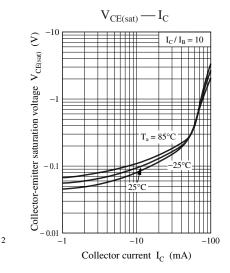
| Parameter                                    | Symbol                          | Conditions   | Min  | Тур   | Max    | Unit |
|--|---------------------------------|--|------|-------|--------|------|
| Collector-base voltage (Emitter open)        | $V_{CBO}$                       | $I_C = -10 \ \mu A, I_E = 0$   | -50  |       |        | V    |
| Collector-emitter voltage (Base open)        | V <sub>CEO</sub>                | $I_{\rm C} = -2 \text{ mA}, I_{\rm B} = 0$                             | -50  |       |        | V    |
| Collector-base cutoff current (Emitter open) | $I_{CBO}$                       | $V_{CB} = -50 \text{ V}, I_{E} = 0$                                    |      |       | - 0.1  | μΑ   |
| Collector-emitter cutoff current (Base open) | I <sub>CEO</sub>                | $V_{CE} = -50 \text{ V}, I_{B} = 0$                                    |      |       | - 0.5  | μΑ   |
| Emitter-base cutoff current (Collector open) | $I_{EBO}$                       | $V_{EB} = -6 \text{ V}, I_C = 0$                                       |      |       | - 0.2  | mA   |
| Forward current transfer ratio               | h <sub>FE</sub>                 | $V_{CE} = -10 \text{ V}, I_{C} = -5 \text{ mA}$                        | 80   |       |        | _    |
| Collector-emitter saturation voltage         | V <sub>CE(sat)</sub>            | $I_C = -10 \text{ mA}, I_B = -0.3 \text{ mA}$                          |      |       | - 0.25 | V    |
| Output voltage high-level                    | V <sub>OH</sub>                 | $V_{CC} = -5 \text{ V}, V_B = -0.5 \text{ V}, R_L = 1 \text{ k}\Omega$ | -4.9 |       |        | V    |
| Output voltage low-level                     | V <sub>OL</sub>                 | $V_{CC} = -5 \text{ V}, V_B = -2.5 \text{ V}, R_L = 1 \text{ k}\Omega$ |      |       | - 0.2  | V    |
| Input resistance                             | R <sub>1</sub>                  |  | -30% | 2.2   | +30%   | kΩ   |
| Resistance ratio                             | R <sub>1</sub> / R <sub>2</sub> |  |      | 0.047 |        | _    |
| Transition frequency                         | $f_T$                           | $V_{CB} = -10 \text{ V}, I_E = 1 \text{ mA}, f = 200 \text{ MHz}$      |      | 80    |        | MHz  |

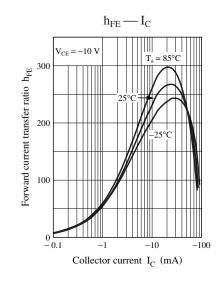
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

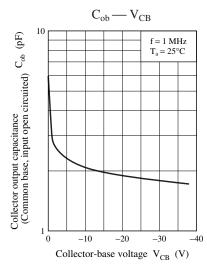
## **Panasonic**

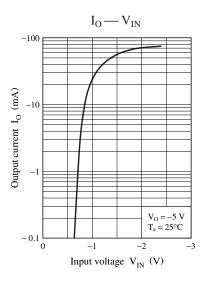


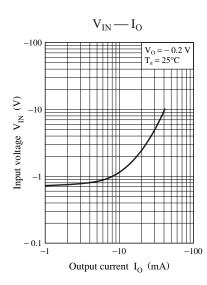












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